

STL60NH3LL

N-channel 30 V - 0.0065 Ω - 30 A - PowerFLAT™ (6x5) ultra low gate charge STripFET™ Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} (max)	I _D
STL60NH3LL	30V	<0.0085Ω	16A

- Improved die-to-footprint ratio
- Very low profile package (1mm max)
- Very low thermal resistance
- Very low gate charge
- Low threshold device

Application

■ Switching applications

Description

This application specific Power MOSFET is the latest generation of STMicroelectronics unique "STripFETTM" technology. The resulting transistor is optimized for low on-resistance and minimal gate charge. The Chip-scaled PowerFLATTM package allows a significant board space saving, still boosting the performance.

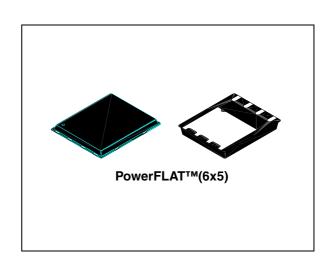


Figure 1. Internal schematic diagram

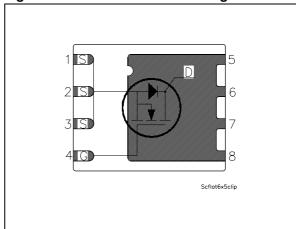


Table 1. Device summary

Order code Marking		Package	Packaging	
STL60NH3LL	L60NH3LL	PowerFLAT™ (6 x 5)	Tape & reel	

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STL60NH3LL Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (V _{GS} = 0)	30	V
V _{GS}	Gate-source voltage	± 16	٧
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25°C	30	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100°C	30	Α
I _D ⁽²⁾	Drain current (continuous) at T _C = 25°C	16	Α
I _{DM} ⁽³⁾	Drain current (pulsed)	64	Α
P _{TOT} ⁽¹⁾	Total dissipation at T _C = 25°C	60	W
P _{TOT} ⁽²⁾	Total dissipation at T _C = 25°C	4	W
	Derating factor	0.03	W/°C
T _j T _{stg}	Operating junction temperature Storage temperature	-55 to 150	°C

- 1. The value is rated according $\boldsymbol{R}_{thi\text{-}C}$ and is limited by wire bonding.
- 2. This value is according $R_{thj\text{-pcb}}$
- 3. Pulse width limited by safe operating area

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case (drain) Max	2.08	°C/W
Rthj-pcb (1)	Thermal resistance junction-pcb Max	31.3	°C/W

^{1.} When mounted on FR-4 board of 1inch², 2 oz. Cu., t<10sec

Table 4. Avalanche data

Symbol	Parameter	Value	Unit
I _{AV}	Not-repetitive avalanche current	7.5	Α
E _{AS}	Single pulse avalanche energy (starting Tj=25°C, Id=lav)	150	mJ

Electrical characteristics STL60NH3LL

2 Electrical characteristics

 $(T_{CASE}=25^{\circ}C \text{ unless otherwise specified})$

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0$	30			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating, V _{DS} = Max rating, @ 125°C			1 10	μ Α μ Α
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{DS} = ± 16 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1			V
R _{DS(on)}	Static drain-source on resistance	V_{GS} = 10 V, I_{D} = 8 A V_{GS} = 4.5 V, I_{D} = 8 A		0.0065 0.0075	0.0085 0.0105	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V_{DS} =25 V, f = 1 MHz, V_{GS} =0		1810 565 41		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 15 \text{ V}, I_{D} = 16 \text{ A},$ $V_{GS} = 4.5 \text{ V}$ (see Figure 16)		18 4.8 5.3	24	nC nC nC
R _G	Gate input resistance	f=1 MHz gate DC bias = 0 test signal level = 20 mV open drain	0.5	1.5	3	Ω

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	V_{DD} = 15 V, I_D = 8 A R_G = 4.7 Ω V_{GS} = 10 V, (see Figure 15)		8 65		ns ns
t _{d(off)}	Turn-off delay time Fall time	V_{DD} = 15 V, I_{D} = 8 A R_{G} = 4.7 Ω V_{GS} = 10 V, (see Figure 15)		30 20		ns ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				16 64	A A
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} = 16 A, V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 16 \text{ V},$ $di/dt = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 20 \text{ V}, T_j = 25^{\circ}\text{C}$ (see Figure 17)		22 32 1.9		ns nC A

^{1.} Pulsed: Pulse duration = 300µs, duty cycle 1.5%

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2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance

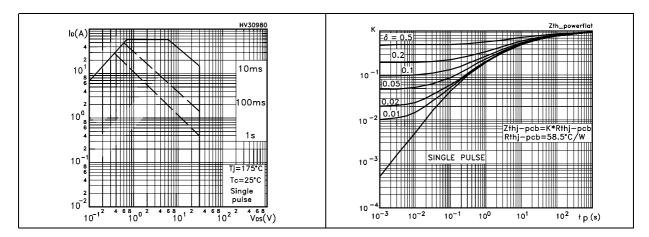


Figure 4. Output characteristics

Figure 5. Transfer characteristics

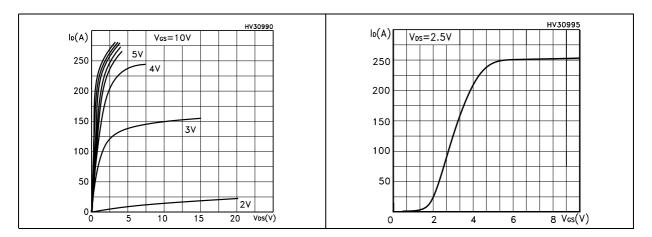
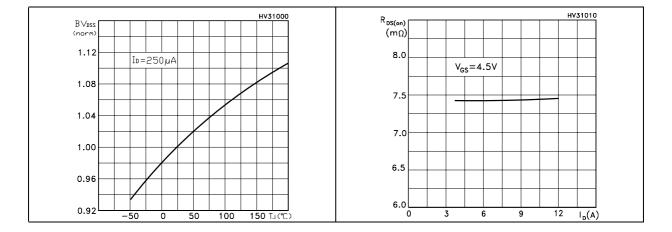


Figure 6. Normalized B_{VDSS} vs. temperature Figure 7. Static drain-source on resistance



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Figure 8. Gate charge vs. gate-source voltage Figure 9. Capacitance variations

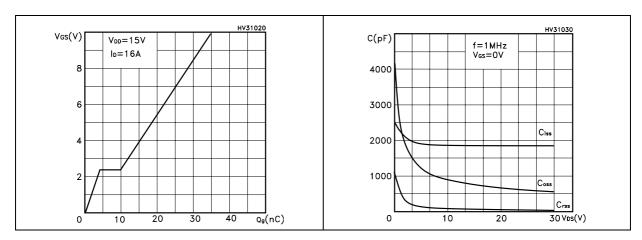


Figure 10. Normalized gate threshold voltage Figure 11. vs. temperature

Figure 11. Normalized on resistance vs. temperature

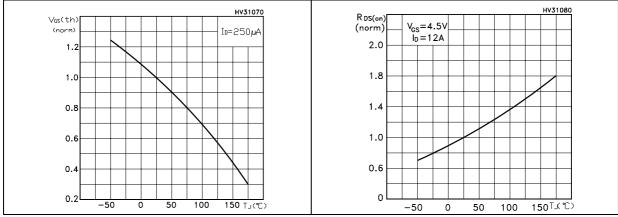
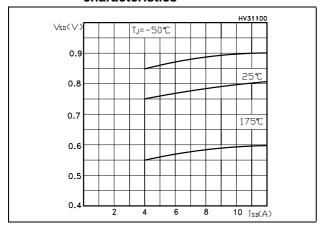
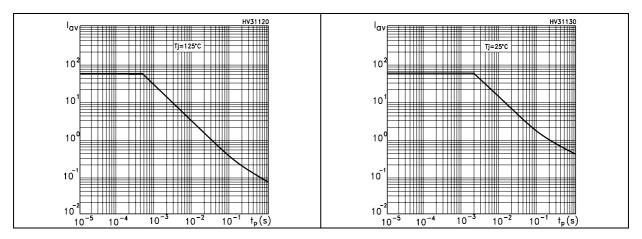


Figure 12. Source-drain diode forward characteristics



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Figure 13. Allowable lav vs Time in Avalanche Figure 14. Allowable lav vs Time in Avalanche



The previous curve gives the single pulse safe operating area for unclamped inductive loads under the following conditions:

$$P_{D(AVE)} = 0.5*(1.3*BV_{DSS}*I_{AV})$$

$$E_{AS(AR)} = P_{D(AVE)} *t_{AV}$$

Where:

I_{AV} is the allowable current in avalanche

P_{D(AVE)} is the average power dissipation in avalanche (single pulse)

t_{AV} is the time in avalanche

STL60NH3LL Test circuit

3 Test circuit

Figure 15. Switching times test circuit for resistive load

Figure 16. Gate charge test circuit

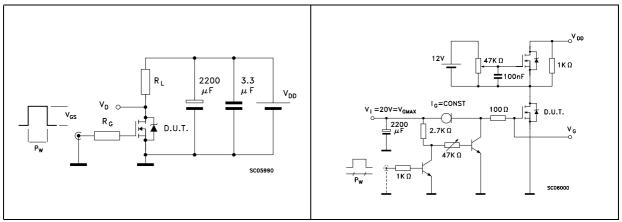


Figure 17. Test circuit for inductive load switching and diode recovery times

Figure 18. Unclamped inductive load test circuit

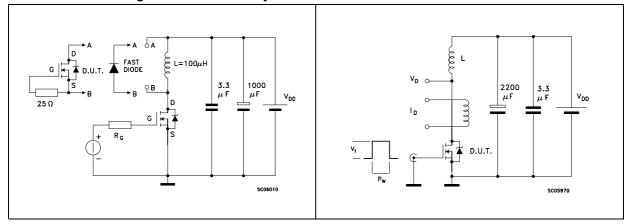
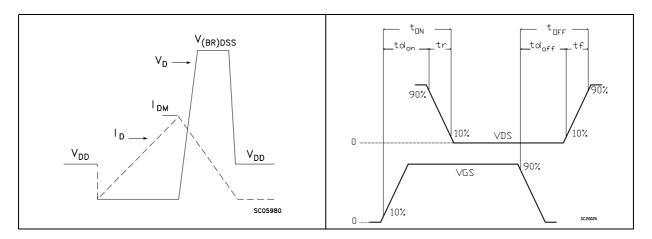


Figure 19. Unclamped inductive waveform

Figure 20. Switching time waveform



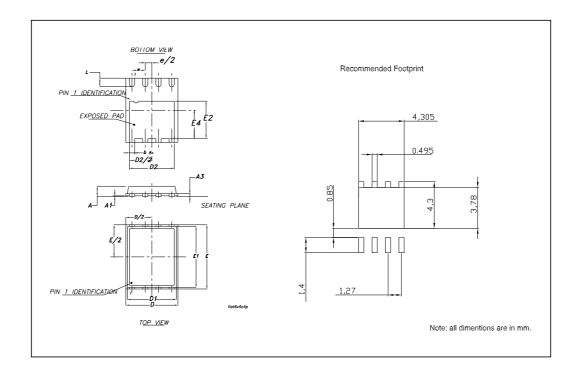
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

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PowerFI ATTM	(6x5)	MECHANICAL	$D\Delta T\Delta$
I OWEII LAI	(UAU		

DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	0.80	0.83	0.93	0.031	0.032	0.036
A1		0.02	0.05		0.0007	0.0019
A3		0.20			0.007	
b	0.35	0.40	0.47	0.013	0.015	0.018
D		5.00			0.196	
D1		4.75			0.187	
D2	4.15	4.20	4.25	0.163	0.165	0.167
E		6.00			0.236	
E1		5.75			0.226	
E2	3.43	3.48	3.53	0.135	0.137	0.139
E4	2.58	2.63	2.68		0.103	0.105
е		1.27			0.050	
L	0.70	0.80	0.90	0.027	0.031	0.035



Revision history STL60NH3LL

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
10-Jan-2006	1	First release
14-Apr-2006	2	New footprint
03-Jul-2006	3	New Ecopack label
01-Aug-2006	4	Modified Figure 2. and Figure 3.
05-Sep-2006	5	New template, no content change
11-Dec-2007	6	Added Table 4: Avalanche data

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